Wireless Test System (WTS)

The WTS is a high-speed, production focused wireless communications physical layer tester.

Featuring the industry's fastest wireless measurement hardware with multiple RF channel configurations, the WTS is multi-standard, multi-antenna, multi-DUT and multi-client ready, designed to reduce manufacturing test time in non-signaling test applications. It provides the easiest route to parallel test deployment with no additional software effort or complexity through virtual instrumentation.

Integrating one or more Vector Signal Transceivers (VST) with up to 16 RF duplex ports, the WTS is designed for calibrating and verifying multiple connectivity/cellular wireless devices in parallel to reduce manufacturing test time. Use of multiple VST modules provides options for true MIMO and 802.11ac 80+80 transmitter/receiver testing.

The standards based measurements are all controlled with an easy-to-use Standard Commands for Programmable Instruments (SCPI) over Ethernet.

Wireless Test Module (WTM)

WTM is a TestStand extension designed for conducting RF measurements and integrating device control within the industry's leading and most trusted factory sequencer environment.

Used with the WTS hardware, WTM software provides the industry's most flexible and easy-to-use multi-DUT/parallel test capable software to accelerate test system deployment. Combining chipset control from leading silicon vendors and built-in control of the WTS hardware using SCPI, the solution provides RF automation which is easy to deploy, integrates into existing processes and tests multiple DUTs.

WTM adds a new dimension of RF testing capability and simplicity to the familiar TestStand environment. It avoids the use of proprietary test vendor executives, GUIs, APIs and RF only test solutions which do not address the challenges of the complete manufacturing automation landscape.

WTM can be supported and extended using the LabView Development Environment to maintain existing chipsets and to create new ones.
## Features at a glance

### Accelerate Test System Development
- Easy to use SCPI interface
- Fast integrated switch control within the instrument for flexible multi-DUT use cases
- Supports virtual instrumentation for connection of multiple clients & test executives
- Multi-DUT scalability with no additional test code development
- Integrated into industry standard TestStand with ready-to-run RF test device sequences and operator GUI
- Integrated chipset solution libraries for leading silicon vendors
- Eliminates programming of common tasks with intuitive test step & test parameter editable RF test plans
- Scalable to multi-DUT with no additional effort
- Expandable, future-proofed development software framework within LabVIEW

### Reduce Manufacturing Test Time
- Fast sequence based test for non-signaling test modes
- Signal broadcast capability for simultaneous receiver testing
- Use of virtual instrumentation to share RF resources efficiently across multiple clients
- High speed, multi-threaded execution engine with parallel execution & thread management
- Multi-DUT test flow execution and configuration management
- Flexible manufacturing test flow by choosing the most optimised process flow for the production line:
  - Sequential
  - Synchronous
  - Asynchronous
- Easy to deploy & maintain with simple reconfiguration & test plan editing even with complex multi-DUT scenarios

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To find out more about our solutions, get in touch with your local Cobham Wireless team by visiting www.cobhamwireless.com/wts